Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/665,126	LAI, JEN-SHOW	
Examiner	Art Unit	

David Buttner

1712

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
528	all	11/17/2006	DB	
525	all	11/17/2006	DB	

RCH STRATEGY)
DATE	EXMR
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